



# GUARANTEED LOW SKEW 3.3V CMOS CLOCK DRIVER/BUFFER

QS53805/A

## FEATURES:

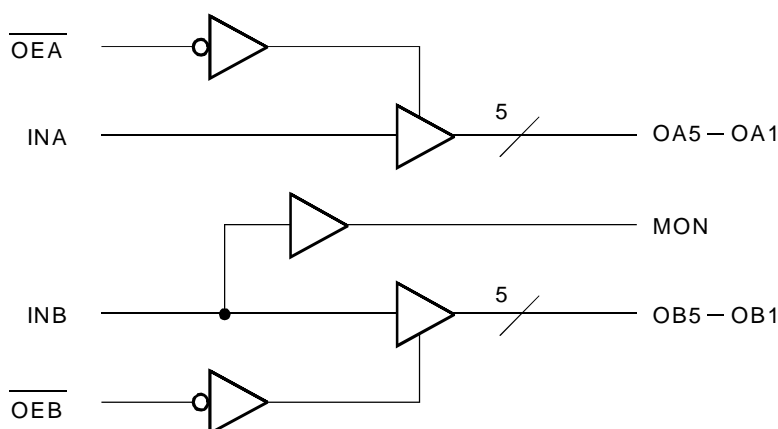
- 10 output, low skew clock signal buffer
- Pinout and function compatible with QS5805T
- JEDEC compatible LVTTTL inputs and outputs
- Input hysteresis for better noise margin
- Monitor output
- Guaranteed low skew:
  - 0.7ns output skew
  - 1.1ns pulse skew
  - 1ns part-to-part skew
- Clock inputs are 5V tolerant
- Std. and A speed grades
- Available in QSOP and SOIC packages

## DESCRIPTION

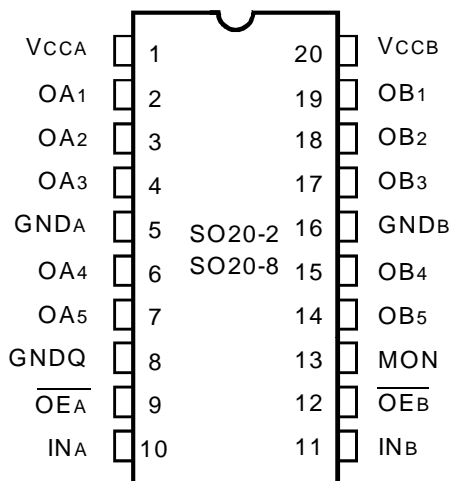
The QS53805 clock buffer/driver circuits can be used for clock buffering schemes where low skew is a key parameter. This device offers two banks of 5 non-inverting outputs. The QS53805 device provides low propagation delay buffering with on-chip skew of 0.7ns for same-transition, same-bank signals. This clock buffer product is designed for use in high performance workstations, embedded and personal computing systems using 3V to 3.6V supply voltages. Several can be used in parallel or scattered throughout a system for guaranteed low skew, system-wide clock distribution networks. The QS53805 can accept 5V input and control signals.

The QS53805 is characterized for operation at -40°C to +85°C.

## FUNCTIONAL BLOCK DIAGRAM



## PIN CONFIGURATION



QSOP/ SOIC  
 TOP VIEW

## ABSOLUTE MAXIMUM RATINGS <sup>(1)</sup>

Symbol	Description	Max.	Unit
V <sub>TERM</sub> <sup>(2)</sup>	Supply Voltage to Ground	- 0.5 to +7	V
	DC Output Voltage V <sub>OUT</sub>	- 0.5 to V <sub>CC</sub> +0.5	V
V <sub>TERM</sub> <sup>(3)</sup>	DC Input Voltage V <sub>IN</sub>	- 0.5 to +7	V
V <sub>AC</sub>	AC Input Voltage (pulse width ≤20ns)	-3	V
I <sub>OUT</sub>	DC Output Current V <sub>IN</sub> < 0	-20	mA
	DC Output Current Max. Sink Current/Pin	120	mA
T <sub>STG</sub>	Storage Temperature	- 65 to +150	°C
T <sub>J</sub>	Junction Temperature	150	°C

### NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- V<sub>CC</sub> Terminals.
- All terminals except V<sub>CC</sub>.

## CAPACITANCE

(T<sub>A</sub> = +25°C, f = 1.0MHz, V<sub>IN</sub> = 0V, V<sub>OUT</sub> = 0V)

Pins	Typ.	Max. <sup>(1)</sup>	Unit
C <sub>IN</sub>	4	6	pF
C <sub>OUT</sub>	8	10	pF

### NOTE:

- This parameter is guaranteed but not production tested.

## RECOMMENDED OPERATING CONDITIONS

Symbol	Description	Min.	Max.	Unit
V <sub>CC</sub>	Power Supply Voltage	3	3.6	V
V <sub>IN</sub>	Input Voltage	0	5.5	V
V <sub>OUT</sub>	Voltage Applied to Outputs	0	V <sub>CC</sub>	V
T <sub>A</sub>	Ambient Operating Temperature	- 40	85	°C

## PIN DESCRIPTION

Pin Names	I/O	Description
$\overline{OEA}$ , $\overline{OEB}$	I	Output Enable
INA, INB	I	Clock Inputs
$\overline{OAn}$ , $\overline{OBn}$	O	Clock Outputs
$\overline{MON}$	O	Monitor Outputs (does not 3-state)

## DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Industrial:  $T_A = -40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ ,  $V_{CC} = 3.3\text{V} \pm 0.3\text{V}$

Symbol	Parameter	Test Conditions	Min.	Typ. <sup>(1)</sup>	Max.	Unit
$V_{IH}$	Input HIGH Voltage	Guaranteed Logic HIGH for Inputs	2	—	5.5	V
$V_{IL}$	Input LOW Voltage	Guaranteed Logic LOW for Inputs	-0.5	—	0.8	V
$V_{IC}$	Clamp Diode Voltage <sup>(3)</sup>	$V_{CC} = \text{Min.}, I_{IN} = -18\text{mA}$	—	-0.7	-1.2	V
$V_{OH}$	Output HIGH Voltage	$V_{CC} = \text{Min.}, I_{OH} = -100\mu\text{A}$	$V_{CC} - 0.2$	—	—	V
		$V_{CC} = \text{Min.}, I_{OH} = -8\text{mA}$	2.4	—	—	V
$V_{OL}$	Output LOW Voltage	$V_{CC} = \text{Min.}, I_{OL} = 100\mu\text{A}$	—	—	0.2	V
		$V_{CC} = \text{Min.}, I_{OL} = 16\text{mA}$	—	—	0.4	V
		$V_{CC} = \text{Min.}, I_{OL} = 24\text{mA}$	—	—	0.5	V
$I_{IN}$	Input Leakage Current	$V_{CC} = \text{Max.}, V_{IN} = V_{CC}$ or GND	—	—	$\pm 1$	$\mu\text{A}$
$I_{OZ}$	Output Leakage Current	$V_{CC} = \text{Max.}, V_{OUT} = V_{CC}$ or GND	—	—	$\pm 1$	$\mu\text{A}$
$I_{OFF}$	Input Power Off Leakage	$V_{CC} = 0\text{V}, V_{IN} = V_{CC}$ or GND	—	—	$\pm 1$	$\mu\text{A}$
$I_{ODH}$	Output HIGH Current <sup>(2)</sup>	$V_{CC} = 3.3\text{V}, V_{IN} = V_{IH}$ or $V_{IL}, V_O = 1.5\text{V}$	-30	-100	-200	mA
$I_{ODL}$	Output LOW Current <sup>(2)</sup>	$V_{CC} = 3.3\text{V}, V_{IN} = V_{IH}$ or $V_{IL}, V_O = 1.5\text{V}$	30	100	200	mA
$I_{OS}$	Short Circuit Current <sup>(2,3)</sup>	$V_{CC} = \text{Max.}, V_{OUT} = \text{GND}$	-60	—	—	mA

### NOTES:

1. Typical values are at  $V_{CC} = 3.3\text{V}, T_A = 25^{\circ}\text{C}$ .
2. Not more than one output should be used to test this high power condition. Duration is less than one second.
3. Guaranteed by design but not tested.

## POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions <sup>(1)</sup>	Typ. <sup>(3)</sup>	Max.	Unit	
$I_{CC}$	Quiescent Power Supply Current	$V_{CC} = \text{Max.}, V_{IN} = \text{GND}$ or $V_{CC}$	0.01	100	$\mu\text{A}$	
$\Delta I_{CC}$	Supply Current per Input HIGH	$V_{CC} = \text{Max.}, V_{IN} = V_{CC} - 0.6\text{V}, f = 0\text{MHz}$	0.1	30	$\mu\text{A}$	
$I_{CCD}$	Dynamic Power Supply Current per Output <sup>(2)</sup>	$V_{CC} = \text{Max.}, \overline{OE_A} = \overline{OE_B} = \text{GND}$ Outputs Toggling at 50% duty cycle	65	100	$\mu\text{A}/\text{MHz}$	
$I_C$	Total Power Supply Current Examples <sup>(2,4)</sup>	$V_{CC} = \text{Max.}, \overline{OE_A} = \overline{OE_B} = \text{GND}$ 50% duty cycle, $f_i = 10\text{MHz}$ five outputs	$V_{IN} = \text{GND}$ or $V_{CC}$	3.5	5.2	mA
			$V_{IN} = \text{GND}$ or 3V	3.5	5.2	mA
		$V_{CC} = \text{Max.}, \overline{OE_A} = \overline{OE_B} = \text{GND}$ 50% duty cycle, $f_i = 2.5\text{MHz}$ All outputs toggling	$V_{IN} = \text{GND}$ or $V_{CC}$	1.8	2.9	mA
			$V_{IN} = \text{GND}$ or 3V	1.8	2.9	mA

### NOTES:

1. For conditions shown as Min. or Max., use the appropriate values specified under DC Electrical Characteristics.
2. Guaranteed by design but not tested.  $C_L = 0\text{pF}$ .
3. Typical values are for reference only. Conditions are  $V_{CC} = 3.3\text{V}, T_A = 25^{\circ}\text{C}$ .
4.  $I_C = I_{CC} + (\Delta I_{CC})(D_H)(N_i) + I_{CCD}(f_o)(N_o)$   
where:  
 $D_H$  = Input Duty Cycle  
 $N_i$  = Number of TTL HIGH inputs at  $D_H$   
 $f_o$  = Output Frequency  
 $N_o$  = Number of outputs at  $f_o$

## SKEW CHARACTERISTICS OVER OPERATING RANGE

$T_A = -40^\circ\text{C}$  to  $+85^\circ\text{C}$ ,  $V_{CC} = 3.3\text{V} \pm 0.3\text{V}$

$C_{LOAD} = 50\text{pF}$ ,  $R_{LOAD} = 500\Omega$  unless otherwise noted.

Symbol	Parameter <sup>(1)</sup>	QS53805		QS53805A		Unit
		Min.	Max.	Min.	Max.	
tsk(01)	Skew between all outputs, same transition, same bank	—	0.7	—	0.7	ns
tsk(02)	Skew between two outputs, same transition, different banks	—	0.8	—	0.8	ns
tsk(P)	Pulse Skew; skew between opposite transitions of the same output (tPHL - tPLH)	—	1.1	—	1.1	ns
tsk(T)	Part-to-part skew <sup>(2)</sup>	—	1.5	—	1	ns

### NOTES:

1. This parameter is guaranteed but not production tested. Skew parameters apply to propagation delays only.
2. tsk(T) only applies to devices of the same transition, part type, temperature, power supply voltage, loading package, and speed grade.

## SWITCHING CHARACTERISTICS OVER OPERATING RANGE

$T_A = -40^\circ\text{C}$  to  $+85^\circ\text{C}$ ,  $V_{CC} = 3.3\text{V} \pm 0.3\text{V}$

$C_{LOAD} = 50\text{pF}$ ,  $R_{LOAD} = 500\Omega$  unless otherwise noted.

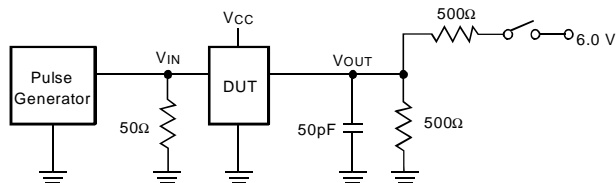
Symbol	Parameter <sup>(1,2)</sup>	QS53805		QS53805A		Unit
		Min.	Max.	Min.	Max.	
tPLH tPHL	Propagation Delay	1.5	6.5	1.5	5.8	ns
tR	Output Rise Time, 0.8V to 2V <sup>(3)</sup>	—	2	—	2	ns
tF	Output Fall Time, 2V to 0.8V <sup>(3)</sup>	—	2	—	2	ns
tPZL tPZH	Output Enable Time	1.5	8	1.5	8	ns
tPLZ tPHZ	Output Disable Time	1.5	7	1.5	7	ns

### NOTES:

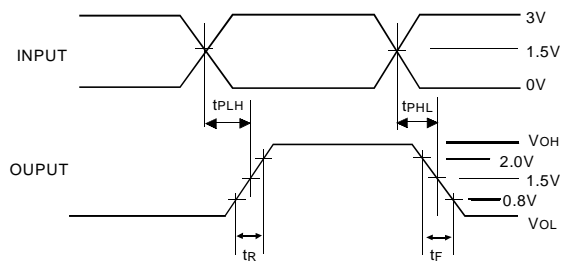
1. Minimums guaranteed but not production tested.
2. The propagation delay other range indicated by Min. and Max. specifications results from process and environmental variables. These propagation delays do not imply limit skew.
3. This parameter is guaranteed but not production tested.

# TEST CIRCUITS AND WAVEFORMS

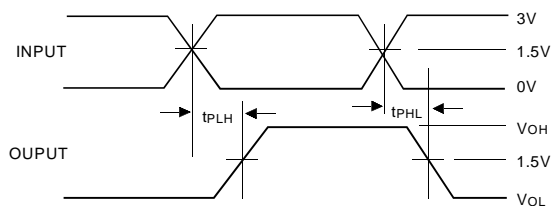
Parameter Tested	Switch Position
tPLZ, tPZL	Closed
All Others	Open



Pulse generator for all pulses:  $f \leq 1.0\text{MHz}$ ;  $t_f \leq 2.5\text{ns}$ ;  $t_R \leq 2.5\text{ns}$

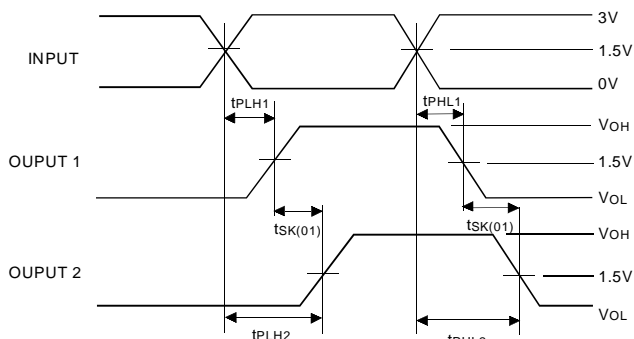


**PROPAGATION DELAY**



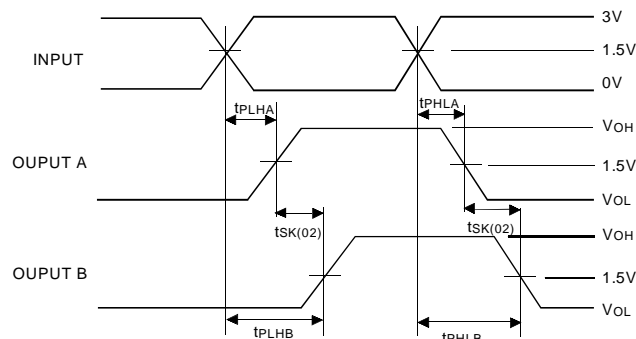
$$t_{SK(p)} = |t_{PHL} - t_{PLH}|$$

**PULSE SKEW — tsk(p)**



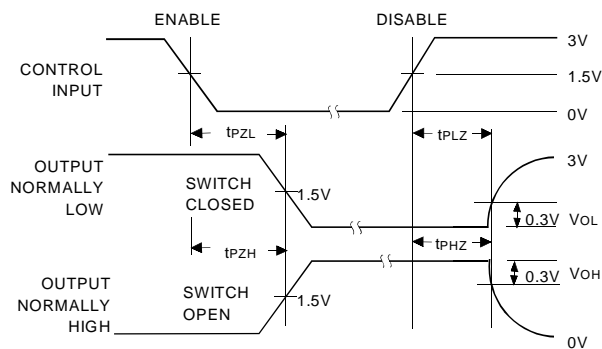
$$t_{SK(01)} = |t_{PLH2} - t_{PLH1}| \text{ or } |t_{PHL2} - t_{PHL1}|$$

**OUTPUT SKEW (SAME BANK) — tsk(01)**

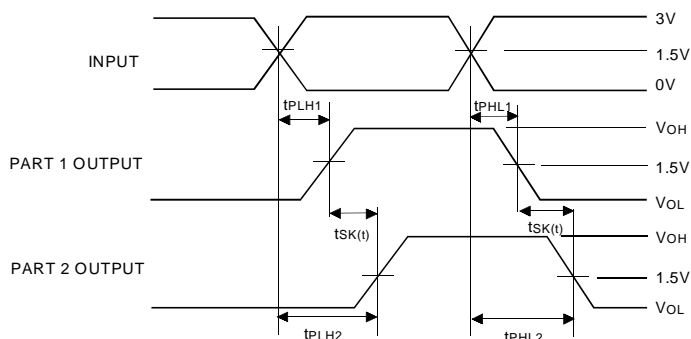


$$t_{SK(02)} = |t_{PLHB} - t_{PLHA}| \text{ or } |t_{PHLB} - t_{PHLA}|$$

**OUPUT SKEW (DIFFERENT BANKS) — tsk(02)**



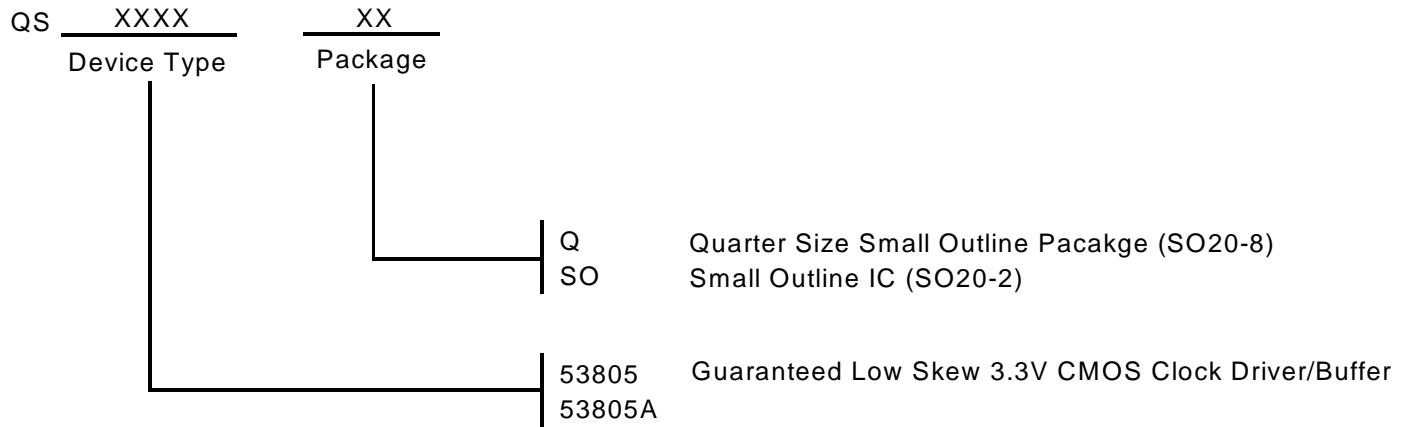
**ENABLE AND DISABLE TIMES**



$$t_{SK(i)} = |t_{PLH2} - t_{PLH1}| \text{ or } |t_{PHL2} - t_{PHL1}|$$

**PART-TO-PART SKEW — tsk(i)**

## ORDERING INFORMATION



**CORPORATE HEADQUARTERS**  
2975 Stender Way  
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800-345-7015 or 408-727-6116  
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